Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/621,800	DEVINE ET AL.
Examiner	Art Unit
Christopher A. Revak	2131

SEARCHED					
Class	Subclass	Date	Examiner		
NONE	NONE	કાહીર્ગ	un		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
709	204,206	3/14/2005	CR		
709	223-229	3/14/2005	CR		
713/150-153,165,166, 168,175,191,193,200- 202		3/14/2005	CR		

SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
BRS Text Search USPAT, DERWENT, JPO, EPO, IBM TDB, US PGPUB, USOCR	8/18/2005	CR
DIALOG Text Search COMPSCI, ELECTRON, SOFTWARE	8/18/2005	CR
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